## Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination DE LA CRUZ, RICHARD Examiner George P. Wyszomierski 1742 Applicant(s)/Patent Under Reexamination DE LA CRUZ, RICHARD Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,571,900	03-1971	Hardesty, Benjamin T.	29/416
	В	US-4,326,326	04-1982	MacDonald, Paul	29/428
	С	US-5,378,295	01-1995	Yamashita et al.	148/654
	D	US-5,433,440	07-1995	Lin, Shih-An	473/342
	E	US-5,669,825	09-1997	Shira, Chester S.	473/324
	F	US-5,797,176	08-1998	Rose et al.	29/527.5
	G	US-5,961,394	10-1999	Minabe, Matsuhiko	473/305
	Н	US-6,001,495	12-1999	Bristow et al.	428/660
	-	US-6,617,537	09-2003	Chiu et al.	219/121.14
	J	US-6,852,041	02-2005	Huang, Chun-Yung	473/342
	К	US-2002/0095762	07-2002	Takeda, Hitoshi	29/447
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N ,	JP-2003-52867	02-2003	Japan		
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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.